

Features

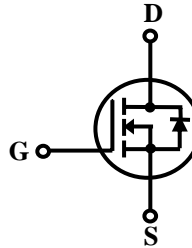
- **N-Channel MOSFET**
- **BV_{DSS} (Minimum) : 600 V**
- **$R_{DS(ON)}$ (Maximum) : 0.65 ohm**
- **I_D : 12 A**
- **Q_g (Typical) : 56 nc**
- **P_D (@TC=25 °C) : 35 W**

General Description

This power MOSFET is produced with advanced VDMOS technology of SAMWIN. This technology enable power MOSFET to have better characteristics, such as fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics. It is mainly suitable for half bridge or full bridge resonant topology like a electronic ballast, and also low power switching mode power appliances.



TO-220
SW F 12N60



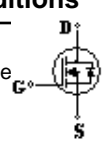
Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain to Source Voltage	600	V
I_D	Continuous Drain Current (@Tc=25°C)	11	A
	Continuous Drain Current (@Tc=100°C)	6.3	A
I_{DM}	Drain Current Pulsed (Note 1)	40	A
V_{GS}	Gate to Source Voltage	±30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	260	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)	3.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Total Power Dissipation (@Tc=25°C)	150	W
	Derating Factor above 25°C	3.6	W/°C
T_{STG}, T_J	Operating junction temperature & Storage temperature	-55 ~ +150	°C
T_L	Maximum Lead Temperature for soldering purpose, 1/8 from Case for 5 seconds.	300	°C

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	-	-	1.09	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	-	-	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	-	-	62.5	°C/W

Electrical Characteristics (Tc=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Value			Units
			Min	Typ	Max	
Off Characteristics						
BV _{DSS}	Drain- Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	600	-	-	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature coefficient	I _D =250uA, referenced to 25°C	-	0.4	-	V/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =600V, V _{GS} =0V, Tc=25°C	-	-	1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =480V, V _{GS} =0V, Tc=125°C	-	-	50	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =20V, V _{DS} =0V	-	-	10	nA
	Gate-Source Leakage Reverse	V _{GS} =-20V, V _{DS} =0V	-	-	-10	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250uA	3.0	3.75	4.5	V
R _{DS(ON)}	Static Drain-Source On-state Resistance	V _{GS} =10V, I _D =5.5A	-	0.65	0.7	ohm
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V, f=1MHz	-	1740		pF
C _{oss}	Output Capacitance		-	195		
C _{rss}	Reverse Transfer Capacitance		-	49		
Dynamic Characteristics						
t _{d(on)}	Turn-on Delay Time	V _{DD} =300V, I _D =5.0A R _G =4.7ohm (Note4,5)	-	-	22.5	ns
t _r	Rise Time		-	-	18.5	
t _{d(off)}	Turn-off Delay Time		-	-	55	
t _f	Fall Time		-	-	31.5	
Q _g	Total Gate Charge	V _{DS} =480V, V _{GS} =10V, I _D =10A (Note4,5)	-	59		nC
Q _{gs}	Gate-Source Charge		-	10	-	
Q _{gd}	Gate-Drain Charge (Miller Charge)		-	32	-	
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit.
I _S	Continuous Source Current	Integral Reverse p-n Junction Diode in the MOSFET 	-	-	11	A
I _{SM}	Pulsed Source Current		-	-	40	
V _{SD}	Diode Forward Voltage	I _S =10A, V _{GS} =0V	-	-	1.6	V
t _{rr}	Reverse Recovery Time	I _S =10A, V _{GS} =0V, di _r /dt=100A/us	-	460	-	ns
Q _{rr}	Reverse Recovery Charge		-	4.2	-	uc

※NOTES

1. Repeativity rating: pulse width limited by junction temperature
2. L=45mH, I_{AS}=10A, V_{DD}=50V, R_G=25ohm, Starting T_J=25°C
3. I_{SD} ≤ 11A, di/dt ≤ 200A/us, V_{DD}=480V, Starting T_J=25°C
4. Pulse Test: Pulse Width ≤ 300us, Duty Cycle ≤ 2%
5. Essentially independent of operating temperature.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

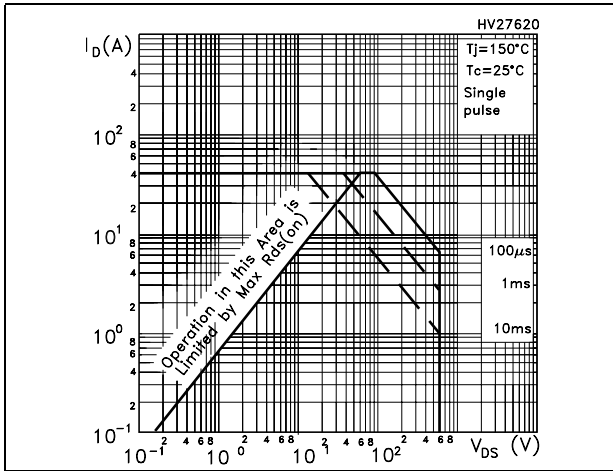


Figure 3. Thermal impedance for TO-220

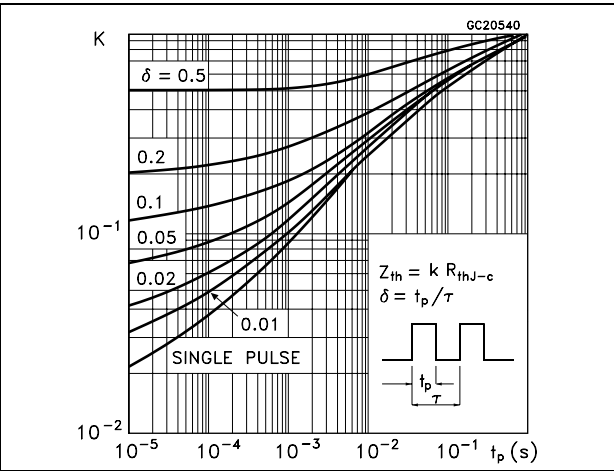


Figure 4. Safe operating area for TO-220FP

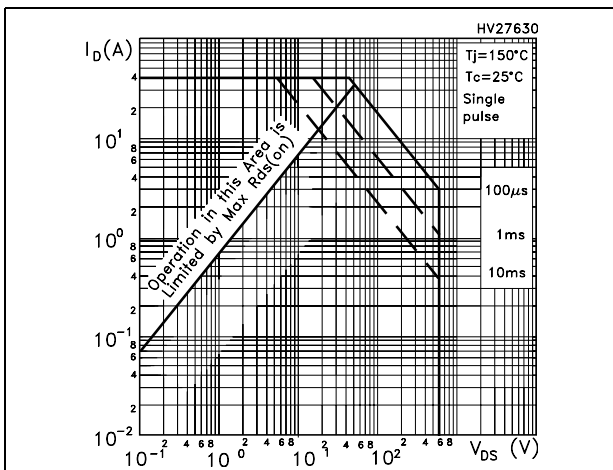


Figure 5. Thermal impedance for TO-220FP

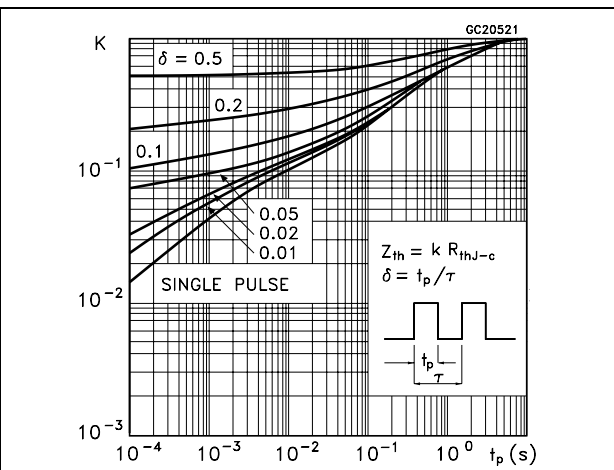


Figure 6. Output characteristics

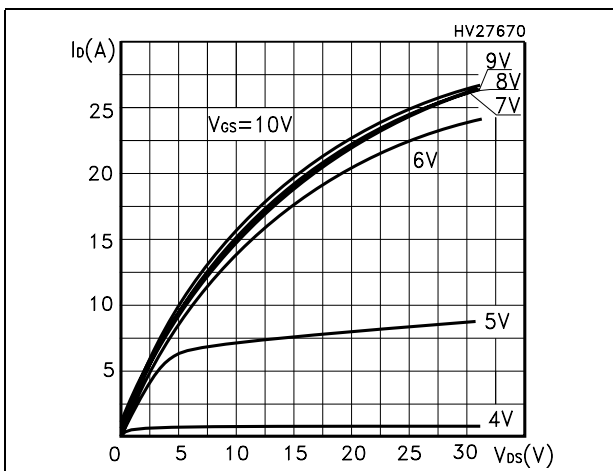


Figure 7. Transfer characteristics

